



Certified Reference Material

Certificate of Analysis

ISO 17034:2016

ISO/IEC 17025:2017

Revision No.: 000

Revision Date: 01/23/2023



Product ID: IARM-FE415-21

validation of analytical methods.

Product Description: Stainless Steel, Martensitic, Alloy 415 / S41500

Description and Intended Use: This Certified Reference Material is covered under the scope of accreditation to ISO 17034 by LGC Standards - Manchester, NH. As an ISO 17034 certified reference material, appropriate use of this material will fulfill the certified reference material and traceability requirements for use in ISO 17025 accredited laboratories. This CRM may come in the form of a solid disk, or chips. The intended use of this CRM may include, but is not limited to, the calibration of instruments and the

Certified Values listed in wt.% with associated uncertainties											
ΑI	0.0018	±0.0005	Cu	0.198	±0.004	0	0.0075	±0.0007	Ti	0.0013	± 0.0005
As	0.0036	±0.0008	Mn	0.640	±0.007	Р	0.028	±0.001	V	0.086	± 0.003
В	0.0008	±0.0003	Мо	0.537	±0.008	S	0.013	±0.001	W	0.042	± 0.002
С	0.018	±0.001	N	0.073	±0.003	Sb	0.0019	±0.0005			
Co	0.065	±0.002	Nb	0.0049	±0.0007	Si	0.42	±0.01			
Cr	11.64	±0.09	Ni	3.55	±0.05	Sn	0.0104	±0.0008			

Indicative Values listed in ppm

Fe Balance Zr 13

Homogeneity and Uncertainty: "Uncertainty" values, as reported adjacent to certified concentration values, are based on a 95% Confidence Interval. These estimated uncertainties include the combined effects of method imprecision, material inhomogeneity, and any bias between methods. Homogeneity data from experimental XRF results are reflected in both the overall statistics and certified data. Homogeneity samples are selected by a systematic sampling procedure. The number of samples may be determined by equation 1, where N_{prod} is the number of units produced and N_{min} is the number of samples used for homogeneity testing. These samples are arranged in a simple randomized design such that each sample is analyzed multiple times by XRF. Homogeneity may also be determined within sample using an applied version of ASTM E826. A single factor ANOVA is used to calculated uncertainty due to inhomogeneity (U_{hom}). Uncertainty of the material is calculated by equation 2, where $H=U_{hom}$, $S=S_{tandard}$ deviation, $t=t_{tandard}$ and $t=t_{tandard}$ and $t=t_{tandard}$ are number of observations.

1.
$$N_{MIN} = \max(10, \sqrt[3]{N_{PROD}})$$
 2. $U_{CRM} = \frac{\sqrt{H^2 + S^2}}{\sqrt{n}} * t$

Certification Laboratories: Much of the analytical work performed to assess this material has been carried out by laboratories with proven competence, as indicated by their accreditation to ISO 17025. It is an implicit requirement for this accreditation that analytical work should be performed with due traceability, via an unbroken chain of comparisons, each with stated uncertainty, to primary standards such as the mole, or to nationally- or internationally-recognised reference materials. Of the individual results herein, some have traceability (to the mole) via primary analytical methods. Some are traceable to substances of known stoichiometry. Most have traceability via commercial solutions. Furthermore, some results have additional traceability to NIST standards, as part of the analytical calibration or process control.

- Applied Technical Services Marietta, GA
- Avon Specialty Metals Ltd Gloucester, England
- EAG Laboratories Liverpool, NY
 IMR Test Labs Lansing, NY
- Laboratory Testing, Inc. Hatfield, PA
- LGC Standards Manchester, NH
- Lithea S.R.O. Brno, Czech Republic
- Lucid Laboratories Pvt Ltd Hyderabad, India
- New Hampshire Materials Laboratory Inc Somersworth, NH
- NSL Analytical Services Cleveland, OH
- Scrooby's Laboratory Service Pty Ltd Benoni, South Africa
- SGS MSi Melrose Park, IL
- · Sheffield Assay Office Sheffield, England

Instructions for Use: The test surface is on the opposite side of the labeled surface, which includes the material identification. The entire thickness of the unit is certified. However, the user is cautioned not to measure disks less than 2 mm thick when using X-ray fluorescence spectrometry. Each packaged disk has been prepared by finishing the test surface using a lathe. The user must determine the correct surface preparation procedure for each analytical technique. The user is cautioned to use care when either resurfacing the disk or performing additional polishing, as these processes may contaminate the surface. The minimum sample size for chips should be individually evaluated based on the analytical technique used; this would typically be greater than 0.1 grams. The material should be stored in a cool, dry location when not in use.

Chips are not recommended for gas analysis.

Period of Validity: The certification of this material is valid indefinitely, within the uncertainty specified, provided the material is handled and stored in accordance with the instructions stated on this certificate. The certification is nullified if the material is damaged, contaminated, otherwise modified, or used in a manner for which it was not intended.

Chuck Goudreau, Certifying Officer

23 January 2023 Certification Date



ISO 17034 Accredited: Reference Materials Producer, Certificate # 2848.02 ISO/IEC 17025 Accredited: Chemical Testing, Certificate # 2848.01



The following data represents all pertinent information reported as it applies to the chemical characterization of this material.

	Al	As	В	С	Co	Cr	Cu	Fe	Mn	Мо	N	Nb	Ni
1	0.0003	0.0015	0.0001	0.0139	0.0562	11.23	0.1800	82.50	0.6190	0.5100	0.0672	0.0027	3.387
2	0.0005	0.0020	0.0002	0.0150	0.0580	11.41	0.1837	82.64	0.6263	0.5130	0.0695	0.0035	3.391
3	0.0006	0.0028	0.0005	0.0162	0.0580	11.45	0.1880	82.65	0.6270	0.5170	0.0703	0.0040	3.406
4	0.0008	0.0029	0.0006	0.0165	0.0587	11.49	0.1887	82.80	0.6293	0.5200	0.0720	0.0041	3.418
5	0.0011	0.0036	0.0007	0.0165	0.0597	11.49	0.1913	83.16	0.6300	0.5200	0.0730	0.0044	3.430
6	0.0020	0.0040	0.0009	0.0167	0.0600	11.52	0.1920		0.6310	0.5280	0.0733	0.0047	3.434
7	0.0020	0.0042	0.0010	0.0171	0.0602	11.52	0.1950		0.6313	0.5294	0.0733	0.0048	3.481
8	0.0022	0.0043	0.0010	0.0175	0.0629	11.53	0.1955		0.6320	0.5350	0.0786	0.0057	3.488
9	0.0022	0.0044	0.0010	0.0182	0.0640	11.54	0.1970		0.6340	0.5377	0.0801	0.0059	3.516
10	0.0025	0.0048	0.0013	0.0190	0.0650	11.55	0.1970		0.6356	0.5382		0.0060	3.541
11	0.0025	0.0050	0.0017	0.0191	0.0656	11.58	0.1973		0.6370	0.5383		0.0060	3.583
12	0.0025	<0.005	<0.0005	0.0200	0.0662	11.59	0.1981		0.6386	0.5400		0.0060	3.599
13	0.0027	<0.005	<0.0010	0.0209	0.0670	11.59	0.1983		0.6392	0.5410		0.0066	3.614
14	0.0029	<0.0050	<0.002	0.0210	0.0670	11.60	0.2000		0.6470	0.5420		<0.008	3.623
15	<0.002	<0.01	<0.002	0.0210	0.0670	11.72	0.2008		0.6523	0.5502		<0.01	3.628
16	< 0.002	<0.01	< 0.005	0.0210	0.0690	11.76	0.2010		0.6540	0.5513			3.630
17	<0.002			0.0212	0.0691	11.78	0.2040		0.6582	0.5560			3.636
18	< 0.005				0.0694	11.88	0.2045		0.6670	0.5618			3.641
19					0.0696	11.90	0.2090		0.6710	0.5651			3.653
20					0.0705	11.95	0.2100						3.688
21					0.0750	11.96	0.2170						3.750
22						12.07							
Mean	0.0018	0.0036	0.0008	0.0183	0.0647	11.64	0.1975	82.75	0.6400	0.5365	0.0730	0.0049	3.549
STDV	0.0009	0.0011	0.0005	0.0023	0.0051	0.21	0.0088	0.25	0.0144	0.0160	0.0041	0.0012	0.109
Certified	0.0018	0.0036	0.0008	0.018	0.065	11.64	0.198	(82.75)	0.640	0.537	0.073	0.0049	3.55
Ucrm	0.0005	0.0008	0.0003	0.001	0.002	0.09	0.004		0.007	0.008	0.003	0.0007	0.05
Methods	O,I,G,IM,X	I,G,IM,O,X	I,G,IM,O	C,O,G	I,O,G,IM,X	I,O,G,X	I,O,G,IM,X	0,1	I,O,X	I,O,X	F,I	O,I,G,IM,X	I,O,G,X

	0	P	S	Sb	Si	Sn	Ti	٧	W	Zr
1	0.0068	0.0210	0.0090	0.0011	0.3660	0.0077	0.0004	0.0760	0.0361	0.0001
2	0.0069	0.0240	0.0098	0.0016	0.3870	0.0080	0.0005	0.0790	0.0368	0.0002
3	0.0070	0.0248	0.0110	0.0016	0.3920	0.0080	0.0007	0.0800	0.0374	0.0012
4	0.0071	0.0250	0.0121	0.0017	0.4010	0.0090	0.0012	0.0810	0.0380	0.0016
5	0.0071	0.0250	0.0122	0.0019	0.4020	0.0094	0.0014	0.0820	0.0382	0.0020
6	0.0075	0.0260	0.0122	0.0020	0.4029	0.0095	0.0017	0.0830	0.0397	0.0020
7	0.0082	0.0263	0.0126	0.0027	0.4056	0.0095	0.0019	0.0830	0.0400	0.0021
8	0.0092	0.0270	0.0126	0.0030	0.4060	0.0100	0.0020	0.0838	0.0404	<0.00005
9		0.0275	0.0126	<0.0010	0.4062	0.0100	0.0020	0.0840	0.0410	<0.0005
10		0.0277	0.0130	<0.0020	0.4097	0.0107	< 0.0005	0.0845	0.0412	<0.0010
11		0.0281	0.0130		0.4110	0.0108	<0.0006	0.0850	0.0420	<0.002
12		0.0281	0.0130		0.4200	0.0110	<0.0010	0.0874	0.0427	<0.002
13		0.0290	0.0140		0.4220	0.0110	< 0.002	0.0885	0.0430	<0.002
14		0.0303	0.0150		0.4260	0.0110	<0.002	0.0890	0.0440	< 0.005
15		0.0305	0.0151		0.4270	0.0118	<0.002	0.0900	0.0440	<0.01
16		0.0306	0.0160		0.4271	0.0120	<0.005	0.0916	0.0451	<0.01
17		0.0310	0.0163		0.4400	0.0120	<0.005	0.0925	0.0459	
18		0.0310	0.0164		0.4500	0.0130	<0.01	0.0930	0.0463	
19		0.0310			0.4568	0.0141		0.0940	0.0476	
20		0.0311			0.4669			0.0946	0.0481	
21		0.0330								
22		0.0330								
Mean	0.0075	0.0282	0.0131	0.0019	0.4163	0.0104	0.0013	0.0861	0.0419	0.0013
STDV	0.0008	0.0031	0.0021	0.0006	0.0243	0.0017	0.0006	0.0054	0.0036	0.0009
Certified	0.0075	0.028	0.013	0.0019	0.42	0.0104	0.0013	0.086	0.042	(0.0013)
UCRM	0.0007	0.001	0.001	0.0005	0.01	0.0008	0.0005	0.003	0.002	
Methods	F	I,O,G,IM,X	C,O,G,I	IM,I	I,O,G,IM,X	I,O,G,IM,X	I,O,G,IM,X	I,O,G,IM,X	I,G,IM,O,X	I,G,IM,O,X

Legend: W = Classical, C = Combustion, F = Fusion, A = AA or GFAA, I = ICP or DCP, IM=ICP-MS, D = DC Arc, O = AES, X = XRF, G = GDAES or GDMS, H = Hollow Cathode AES

